

**Search Notes**

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Sangwoo Ahn

Applicant(s)/Patent under  
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VIERICH ET AL.

Art Unit

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**SEARCHED**

Class	Subclass	Date	Examiner
707	1-10	1/30/2006	SW

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Search History Attached (USPGPUB, USPAT, JPO, EPO, DERWENT, IBM_TDB) text search only	1/30/2006	SW
Consulted Khanh Pham	1/30/2006	SW